

**Search Notes**

Application/Control No.

10/533,860

Examiner

Jason M. Perilla

Applicant(s)/Patent under  
Reexamination

TOUCHAIS ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	295	1/15/2008	JP
	296	1/15/2008	JP
	297	1/15/2008	JP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB	1/15/2008	JP
Inventor Name Search EAST/EDAN	1/15/2008	JP